Field-averaging micro lenses that synthesize highly uniform illumination in coherent EUV optical systems

Christopher N. Anderson (1), Patrick P. Naulleau (2), Paul Denham (2), Drew Kemp (2) and Senajith Rekawa (2)

MOTIVATION

- Illumination uniformity and reproducibility in EUV microfield exposure tools is critical to many aspects of the EUV lithography development task.
- To address this concern, field-integrating fly's eye elements are often used in illuminator designs.

SEMATECH BERKELEY MET

- 0.3 NA Zeiss optic in 5x reduction configuration
- 600x200 μm field size at wafer Support for arbitrary pupil fills with Fourier-synthesis scanning illuminator
- Ultrahigh resolution capabilities from a conventional projection EUV system



and Ismi are servicemarks of SEMATECH, Inc. SEMATECH, the SEMATECH inced Technology Development Facility, ATDF, and the ATDF logo are registerer rks of SEMATECH, Inc. All other servicemarks and trademarks are the property

GOALS

- · Expand uniformly illuminated field size to match capabilities of MET projection optics (3-mm x 1-mm at mask)
- Enable programmable field size
- Maintain system throughput
- Maintain programmable coherence (pupil fill) functionality of the system



POST-UPGRADE SYSTEM PERFORMANCE

Reticle Before Upgrade	Printed Clear Field
Reticle After Upgrade	Printed Flare Field
Printing data to the right following the upgrade. space data courtesy of Wallow, AMD	ht is Line- Tom

- Before and after pictures of reticle field and printed clear fields show improved performance.
- Lithographically measured uniformity = 6.5% peak-to-valley across 9 points spanning the field

CONCLUSIONS

- We've developed a field-averaging scanning-Fly's Eye stage enabling nonuniform, high-coherence sources to be used in applications requiring high illumination uniformity
- The system has been successfully integrated into the existing illuminator of the SEMATECH Berkeley MET and we report post-upgrade intensity uniformity across the 200x600 µm wafer-side field of view of 6.5%.

ACKNOWLEDGEMENTS

• The authors are grateful for support from the National Science Foundation EUV Science and Technology Center. This research was also supported by SEMATECH (Kim Dean, program manager).





